

Search Notes

Application/Control No.

10/574,528

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	142	1/6/2008	PN
	302		
	296		
333	214		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
330	142	1/6/2008	PN
	302		
	296		
333/214			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	1/6/2008	PN